SCES119D - JULY 1997 - REVISED MAY 1999

- **EPIC™** (Enhanced-Performance Implanted CMOS) Submicron Process
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic Small-Outline (DW), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages

(TOP VIEW) 20 🛮 V_{CC} DIR [19 OE A2 **∏** 3 18 B1 A3 **∏** 4 17 **∏** B2 A4 **∏** 5 16 **∏** B3 A5 **∏** 6 15 B4 A6 **∏** 7 14 N B5 А7 П 8 13 D B6 A8 🛮 9 12 B7 GND ¶10 11 **|** B8

DGV. DW. OR PW PACKAGE

description

This octal bus transceiver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH245 is designed for asynchronous communication between data buses. The device transmits data from the A bus to the B bus or from the B bus to the A bus, depending on the logic level at the direction-control (DIR) input. The output-enable (\overline{OE}) input can be used to disable the device so the buses are effectively isolated.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH245 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE

INP	UTS	OPERATION
OE	DIR	OPERATION
L	L	B data to A bus
L	Н	A data to B bus
Н	Χ	Isolation

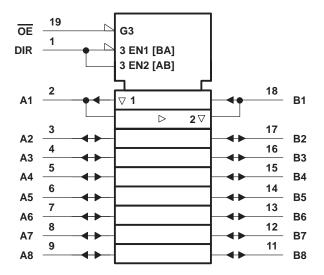


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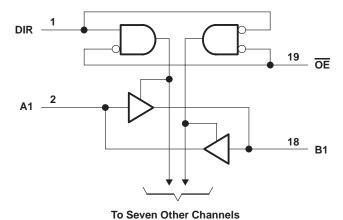


logic symbol†



 $[\]ensuremath{^{\dagger}}$ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	
Input voltage range, V _I : Except I/O ports (see Note 1)	
I/O ports (see Notes 1 and 2)	0.5 V to V _{CC} + 0.5 V
Output voltage range, VO (see Notes 1 and 2)	
Input clamp current, $I_{ K }(V_{ I } < 0)$	
Output clamp current, I _{OK} (V _O < 0)	
Continuous output current, IO	±50 mA
Continuous current through V _{CC} or GND	±100 mA
Package thermal impedance, θ _{JA} (see Note 3): DGV package	146°C/W
DW package	97°C/W
PW package	128°C/W
Storage temperature range, T _{stq}	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.

- 2. This value is limited to 4.6 V maximum.
- 3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT	
Vcc	Supply voltage		1.65	3.6	V	
		$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	0.65 × V _{CC}			
\vee_{IH}	High-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7		V	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2			
		$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$		0.35 × V _{CC}		
VIH H	Low-level input voltage $V_{CC} = 2.3 \text{ V}$			0.7	V	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$		0.8		
٧ _I	Input voltage	-	0	Vcc	V	
VO	Output voltage		0	Vcc	V	
		V _{CC} = 1.65 V		-4		
1	High-level output current	V _{CC} = 2.3 V		-12	mA	
ЮН		V _{CC} = 2.7 V		-12		
		V _{CC} = 3 V		-24		
		V _{CC} = 1.65 V	4			
1	Laveland autout aumont	V _{CC} = 2.3 V		12		
IOL	Low-level output current	V _{CC} = 2.7 V	12		mA	
		V _{CC} = 3 V		24		
Δt/Δν	Input transition rise or fall rate	-		10	ns/V	
T _A	Operating free-air temperature		-40	85	°C	

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



SN74ALVCH245 **OCTAL BUS TRANSCEIVER WITH 3-STATE OUTPUTS**

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PA	RAMETER	TEST C	ONDITIONS	Vcc	MIN	TYP [†]	MAX	UNIT
		I _{OH} = -100 μA		1.65 V to 3.6 V	V _{CC} -0.	.2		
		I _{OH} = -4 mA	1.65 V	1.2				
Voн		I _{OH} = -6 mA	2.3 V	2				
			2.3 V	1.7			V	
		I _{OH} = -12 mA		2.7 V	2.2			
				3 V	2.4			
		I _{OH} = -24 mA	3 V	2				
		I _{OL} = 100 μA		1.65 V to 3.6 V			0.2	
		I _{OL} = 4 mA		1.65 V			0.45	
VOL	I _{OL} = 6 mA		2.3 V			0.4	V	
	I _{OL} = 12 mA		2.3 V			0.7	V	
		IOL = 12 IIIA	2.7 V			0.4		
		I _{OL} = 24 mA	3 V			0.55		
lį		$V_I = V_{CC}$ or GND		3.6 V			±5	μΑ
		V _I = 0.58 V		1.65 V	25			
		V _I = 1.07 V	1.65 V	-25			. 1	
		V _I = 0.7 V		2.3 V	45			
I _I (hold)		V _I = 1.7 V		2.3 V	-45			μΑ
		V _I = 0.8 V		3 V	75			
		V _I = 2 V		3 V	-75			
		$V_1 = 0 \text{ to } 3.6 \text{ V}^{\ddagger}$		3.6 V			±500	
loz§		$V_O = V_{CC}$ or GND,		3.6 V			±10	μΑ
ICC		$V_I = V_{CC}$ or GND,	IO = 0	3.6 V			10	μΑ
∆ICC		One input at V _{CC} – 0.6 V,	Other inputs at V _{CC} or GND	3 V to 3.6 V			750	μΑ
Ci	Control inputs	$V_I = V_{CC}$ or GND		3.3 V		4.5		pF
C _{io}	A or B ports	$V_O = V_{CC}$ or GND	<u> </u>	3.3 V		12		pF

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} =		V _{CC} =		V _{CC} =	2.7 V	V _{CC} =	3.3 V 3 V	UNIT
	(INFOT)	(001F01)	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
^t pd	A or B	B or A	1.5	6	1	3.5		3.6	1.3	3.4	ns
t _{en}	ŌĒ	A or B	3.4	8.6	2	6		6.3	1.6	5.5	ns
^t dis	ŌĒ	A or B	2.7	8	1	4.8		5.3	1.7	5.5	ns

operating characteristics, T_A = 25°C

PARAMETER		TEST CONDITIONS	V _{CC} = 1.8 V TYP	V _{CC} = 2.5 V TYP	V _{CC} = 3.3 V	UNIT		
ſ	<u> </u>	Power dissipation capacitance	Outputs enabled	C _L = 0,	25	28	31	pF
C _{pd}	Cpd	per transceiver	Outputs disabled	f = 10 MHz	0	0	0	pr

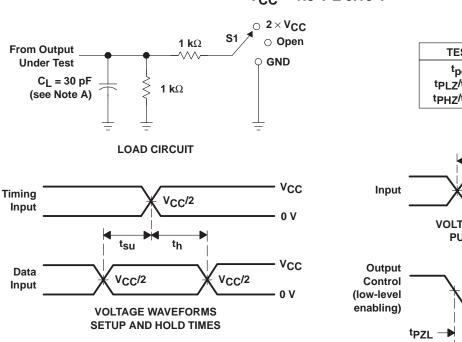


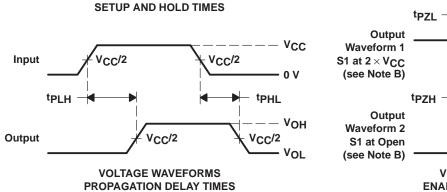
[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C. ‡ This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

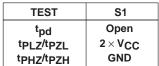
[§] For I/O ports, the parameter IOZ includes the input leakage current.

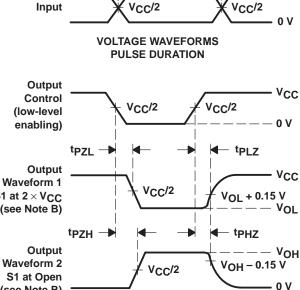
VCC

PARAMETER MEASUREMENT INFORMATION $V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}$









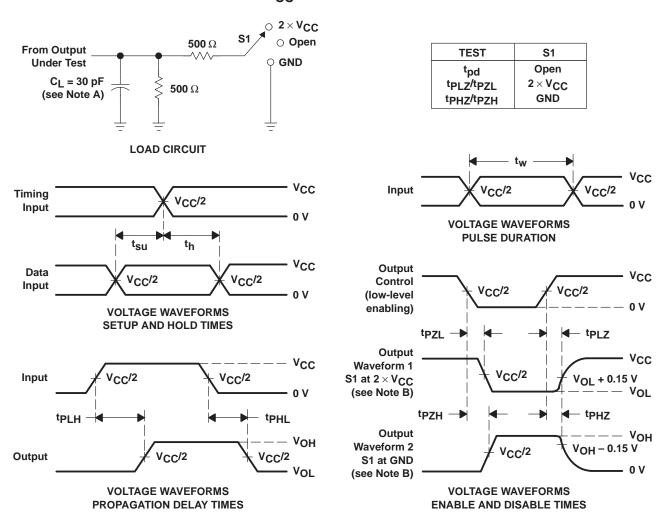
VOLTAGE WAVEFORMS ENABLE AND DISABLE TIMES

NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_f \leq 2$ ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpl 7 and tpH7 are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION $V_{CC} = 2.5 V \pm 0.2 V$



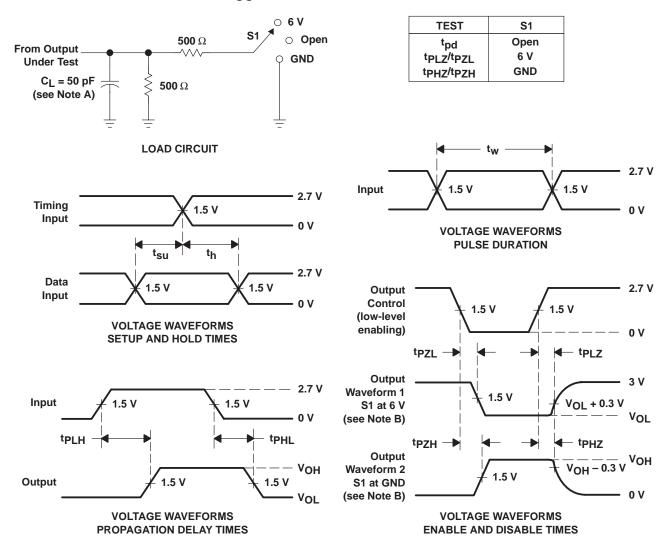
NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_f \leq$ 2 ns, $t_f \leq$ 2 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpzl and tpzH are the same as ten.
- G. tpl H and tpHI are the same as tpd.

Figure 2. Load Circuit and Voltage Waveforms



PARAMETER MEASUREMENT INFORMATION V_{CC} = 2.7 V AND 3.3 V \pm 0.3 V



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_{O} = 50 \, \Omega$, $t_{r} \leq 2.5 \, \text{ns}$, $t_{f} \leq 2.5 \, \text{ns}$.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpZL and tpZH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 3. Load Circuit and Voltage Waveforms

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